Application/Control No. O9/430,437 Reexamination DEY ET AL. Examiner Charles A. Bieneman Applicant(s)/Patent Under Reexamination DEY ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,569,206 B1	05-2003	Dey et al.	715/501.1
	В	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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FOREIGN PATENT DOCUMENTS

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